

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Finarov, Moshe; Dvir, Eran; Haimovich, Eli; Shulman, Benjamin
Assignee: Nova Measuring Instruments, Inc.
Title: APPARATUS FOR OPTICAL INSPECTION OF WAFERS DURING POLISHING
Serial No.: Unknown Filed: Herewith
Examiner: Unknown Group Art Unit: Unknown
Docket No.: M-3417-2C US

San Jose, California
February 4, 2000

BOX PATENT APPLICATION
ASSISTANT COMMISSIONER FOR PATENTS
Washington, D. C. 20231

**REQUEST TO AMEND DRAWINGS
UNDER 37 C.F.R. § 1.121**

Sir:

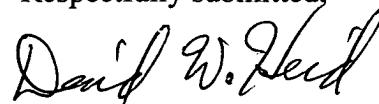
Pursuant to 37 C.F.R. §1.121, Applicant(s) respectfully request(s) permission to amend Figs. 6, 7, 8 and 9 as shown in red on the accompanying sheets.

Should the Examiner have any questions concerning this request, the Examiner is invited to call the undersigned at (408) 453-9200.

EXPRESS MAIL LABEL NO:

EL 375 478 733 US

Respectfully submitted,



David W. Heid
Attorney for Applicant(s)
Reg. No. 25,875

LAW OFFICES OF
SKJERVEN, MORRILL,
MacPHERSON, FRANKLIN
& FRIEL LLP

2 Gav Yam Ctr., 2nd floor
7 Sbenkar Street
46733 Herzlia
Israel 25 METRO DRIVE
SUITE 700
SAN JOSE, CA 95110